## Experiment 2

# Output Characteristics Analysis of Fixed Bias and Voltage Divider Bias

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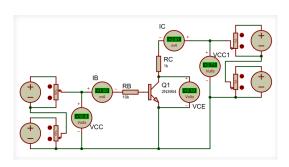
### 1 Objective

- 1. To determine the output characteristics of fixed bias configuration
- 2. To determine the output characteristics of voltage divider bias configuration

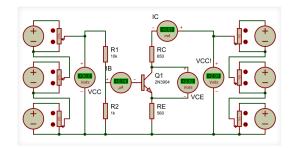
## 2 Apparatus

- 1. Transistor (2N3904 n-p-n)
- 2. Resistors  $(10k\Omega, 1k\Omega, 650\Omega, 560\Omega)$
- 3. Multimeter
- 4. Ammeters (mA and  $\mu$ A)
- 5. Breadboard
- 6. Wires
- 7. DC Power Supply (0-30V)

#### 3 Circuit Diagram



(a) Fixed Bias Configuration



(b) Voltage Divider Bias Configuration

Figure 1: Circuit Diagrams

# 4 Data Analysis

## 4.1 Fixed Bias Configuration

#### 4.1.1 Data Tables

Simulation Data			Pr	Errors								
$I_B = 0\mu A$												
$V_{CC}$ (V)	$V_{CE}$ (V)	$I_C \text{ (mA)}$	$V_{CC}$ (V)	$V_{CE}$ (V)	$I_C (\mathrm{mA})$	$\%V_{CE}$	$\%I_{C}$					
0	0	0	0	0	0	0	0					
2.7	2.7	0	2.7	2.02	0	25.19	0					
5.6	5.6	0	5.6	5.01	0	10.54	0					
9	9	0	9	8.16	0	9.33	0					
12	12	0	12	10.5	0	12.5	0					
15.3	15.3	0	15.3	13.9	0	9.15	0					
18.4	18.4	0	18.4	17.5	0	4.89	0					
21.8	21.8	0	21.8	21.27	0	2.43	0					
25.2	25.2	0	25.2	24.3	0	3.57	0					
28.2	28.2	0	28.2	27.2	0	3.55	0					
$I_B = 11\mu A$												
$V_{CC}$ (V)	$V_{CE}$ (V)	$I_C \text{ (mA)}$	$V_{CC}$ (V)	$V_{CE}$ (V)	$I_C \text{ (mA)}$	$\%V_{CE}$	$\%I_{C}$					
0	0	0	0	0	0	0	0					
2.73	1.86	0.86	2.7	1.56	1	16.13	16.28					
5.65	4.74	0.91	5.6	4.2	1	11.39	9.89					
8.98	8.01	0.97	9	7.33	1	8.49	3.09					
11.9	10.9	1.02	12	10.01	1	8.17	1.96					
15.3	14.2	1.08	15.3	13.69	1	3.59	7.41					
18.4	17.2	1.13	18.4	16.63	1.1	3.31	2.65					
21.8	20.6	1.19	21.8	20.1	1.2	2.43	0.84					
25.2	24	1.25	25.2	23.07	1.2	3.88	4					
28.2	26.9	1.3	28.2	25	1.2	7.06	7.69					

Table 1: Data Analysis for Fixed Bias Configuration

## 4.2 Voltage Divider Bias Configuration

Simulation Data			Pr	Errors							
$I_B = 0\mu A$											
$V_{CC}$ (V)	$V_{CE}$ (V)	$I_C \text{ (mA)}$	$V_{CC}$ (V)	$V_{CE}$ (V)	$I_C (\mathrm{mA})$	$%V_{CE}$	$\%I_{C}$				
0	0	0	0	0	0	0	0				
3	3	0	3	2.7	0	10	0				
8	8	0	8	7.6	0	5	0				
10	10	0	10	9.3	0	7	0				
14	14	0	14	13.87	0	0.93	0				
17	17	0	17	16.4	0	3.53	0				
20	20	0	20	19.1	0	4.5	0				
24	24	0	24	23.6	0	1.67	0				
27	27	0	27	26.7	0	1.11	0				
$I_B = 0.14\mu A$											
$V_{CC}$ (V)	$V_{CE}$ (V)	$I_C \text{ (mA)}$	$V_{CC}$ (V)	$V_{CE}$ (V)	$I_C \text{ (mA)}$	$\%V_{CE}$	$\%I_{C}$				
0	0	0	0	0	0	0	0				
3	2.91	0.07	3	2.91	0.07	3.09	90				
8	7.9	0.08	8	7.9	0.07	1.27	88.57				
10.7	10.6	0.09	10.7	10.6	0.07	0.94	87.14				
14.7	14.5	0.1	14.7	14.5	0.11	1.38	10				
17.7	17.5	0.11	17.7	17.5	0.11	1.14	0				
20.7	20.5	0.12	20.7	20.5	0.11	0.98	8.33				
24.7	24.5	0.13	24.7	24.5	0.11	0.82	15.38				
27.6	27.5	0.14	27.6	27.5	0.11	0.36	21.43				

Table 2: Data Analysis for Voltage Divider Bias Configuration

#### 5 Graphs

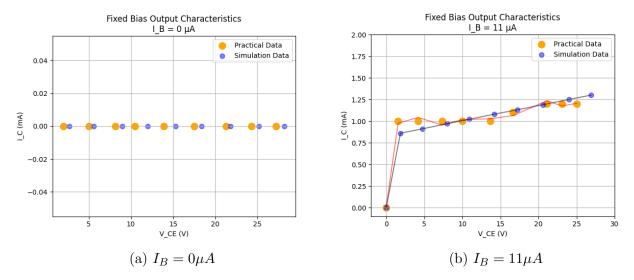


Figure 2: Output Characteristics of Fixed Bias Configuration

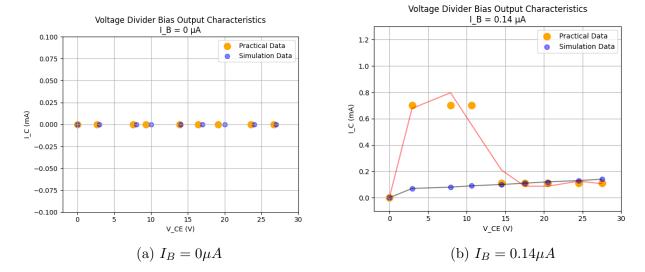


Figure 3: Output Characteristics of Voltage Divider Bias Configuration

From the graphs, we can see that the simulation and the practical data are not exactly equal. This is due to some technical errors and precision errors. From the graph, a connecting line drawn between  $V_{CE} = 0$  and  $I_C = 0$  will intersect the output characteristic plot at a point called the Q-point or operational point. This Q-point can be modified by varying the values of  $V_{CC}$  and  $R_C$ .

#### 6 Discussion

- (a) The experiment was conducted to learn about the biasing of transistors. Two biasings were analyzed: fixed bias, and voltage divider bias.
- (b) All the biases were made using a 2N3904 n-p-n transistor in a common-emitter configuration.
- (c) The output characteristics of the two biasing configurations were plotted and analyzed.
- (d) The output characteristic graphs for simulation and practical data were plotted and compared.
- (e) Error of the practical data from the simulation data was calculated.
- (f) The errors were considered to happen due to technical errors and precision errors.
- (g) More accurate equipment could be used to reduce the errors.